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Substitute for form 1449/PTO

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INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet

2

of

2

Application Number

10/801,981

Filing Date

03/16/2004

First Named Inventor

Diane K. Stewart

Art Unit

N/A

Examiner Name

N/A

Attorney Docket Number

F118 ACIP

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
BES	I	C.K. CRAWFORD, Charge Neutralization Using Very Low Energy Ions, Scanning Electron Microscopy, 1979, II, SEM Inc., USA	
BES	J	ALBERT FOLCH ET AL., High Vacuum Versus, "Environmental" Electron Beam Deposition, Jul/Aug. 1996, B 14(4), PP. 2609-2614, J. Vac. Sci.	
BES	K	YUKINORI OCHIAI, Electron-Beam-Induced Deposition of Copper with Low Resistivity, Nov/Dec. 1996, B 14(6), PP. 3887-3891, J. Vac. Sci. Technol.	

Examiner  
Signature

Bernard Souw

Date  
Considered

03/23/05

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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PTO/SB/08A (08-03)

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Substitute for form 1449/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Use as many sheets as necessary)</i>				<b>Complete if Known</b>	
				Application Number	10/801,981
				Filing Date	03/16/2004
				First Named Inventor	Diane K. Stewart
				Art Unit	3641
				Examiner Name	N/A
Sheet	2	of	2	Attorney Docket Number	F118ACIP

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Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
BES	C	WITOLD SLOWKO AND HERBERT PRASOL, "Micro-Sphere Plate as an Electron Detector at Low Vacuum," Vacuum, Vol. 67, (2002) pp. 191-198	
BES	D	M. JACKA, M. ZADRAZIL AND F. LOPOUR, "A Differentially Pumped Secondary Electron Detector for Low-Vacuum Scanning Electron Microscopy," Scanning, Vol. 25, (2003) pp. 243-246	
BES	E	WITOLD SLOWKO, "Secondary Electron Detector with a Micro-Porous Plate for Environmental SEM," Vacuum, Vol. 63, (2001) pp. 457-461	

Examiner Signature	Bernard Souw	Date Considered	03/23/05
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